

<b>Search Notes</b>  	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10708730	HO ET AL.
	<b>Examiner</b>  Detschel, Marissa J	<b>Art Unit</b>  2877

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
356	328, 334	12/8/06	MJD

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Updated EAST search from 5/5/06	12/8/06	MJD
Consulted Fannie Evans on allowable subject matter	1/11/07	MJD
Search terms: curved, concave, grating, path difference, arc length, groove, distance, position, slit, detector	1/4/07	MJD

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>